

dry benzene. The solution was stirred until the starting material disappeared, as determined by thin-layer chromatography. The crude product was purified by column chromatography using petroleum ether–benzene (9:1) and crystallized from petroleum ether–benzene (1:1) solution; m.p. 503 K.

Crystal data

C ₂₈ H ₂₀ N ₂ O	Cu K α radiation
M _r = 400.46	λ = 1.5418 Å
Orthorhombic	Cell parameters from 25 reflections
Pbc _a	θ = 10–25°
<i>a</i> = 11.188 (4) Å	μ = 0.608 mm ⁻¹
<i>b</i> = 13.672 (9) Å	<i>T</i> = 293 (2) K
<i>c</i> = 27.352 (2) Å	Rectangular
V = 4183.8 (4) Å ³	0.40 × 0.18 × 0.15 mm
Z = 8	Yellow
D _x = 1.272 Mg m ⁻³	
D _m not measured	

Data collection

Enraf–Nonius CAD-4 diffractometer	$\theta_{\text{max}} = 67^\circ$
$\omega/2\theta$ scans	$h = 0 \rightarrow 13$
Absorption correction: none	$k = 0 \rightarrow 16$
3728 measured reflections	$l = 0 \rightarrow 32$
3727 independent reflections	3 standard reflections every 100 reflections
2940 reflections with $I > 2\sigma(I)$	intensity decay: <1.5%

Refinement

Refinement on F^2	$(\Delta/\sigma)_{\text{max}} = -0.005$
$R[F^2 > 2\sigma(F^2)] = 0.059$	$\Delta\rho_{\text{max}} = 0.278 \text{ e } \text{\AA}^{-3}$
$wR(F^2) = 0.174$	$\Delta\rho_{\text{min}} = -0.155 \text{ e } \text{\AA}^{-3}$
$S = 1.103$	Extinction correction: none
3727 reflections	Scattering factors from <i>International Tables for Crystallography</i> (Vol. C)
360 parameters	
All H atoms refined	
$w = 1/[\sigma^2(F_o^2) + (0.1001P)^2 + 0.7638P]$	
where $P = (F_o^2 + 2F_c^2)/3$	

Table 1. Selected geometric parameters (Å, °)

N1—C16	1.278 (2)	C1—C14	1.534 (3)
N1—N2	1.378 (2)	C1—C15	1.562 (3)
N2—C23	1.398 (3)	C2—C7	1.394 (3)
N2—C1	1.490 (3)	C7—C8	1.476 (3)
O1—C8	1.216 (3)	C8—C9	1.479 (3)
C1—C2	1.515 (3)	C9—C14	1.390 (3)
C16—N1—N2	109.6 (2)	C2—C1—C15	109.6 (2)
N1—N2—C23	118.6 (2)	C14—C1—C15	109.0 (2)
N1—N2—C1	112.82 (15)	C16—C15—C1	102.7 (2)
C23—N2—C1	125.7 (2)	N1—C16—C17	121.9 (2)
N2—C1—C2	112.0 (2)	N1—C16—C15	113.6 (2)
N2—C1—C14	111.4 (2)	C17—C16—C15	124.4 (2)
C2—C1—C14	113.7 (2)	C24—C23—N2	121.0 (2)
N2—C1—C15	100.26 (15)	N2—C23—C28	120.3 (2)

Data collection: *CAD-4 Software* (Enraf–Nonius, 1989). Cell refinement: *CAD-4 Software*. Program(s) used to solve structure: *SHELXS86* (Sheldrick, 1990). Program(s) used to refine structure: *SHELXL93* (Sheldrick, 1993). Molecular graphics: *ORTEP92* (Vickovic, 1994). Software used to prepare material for publication: *SHELXL93* and *PARST* (Nardelli, 1983).

SB thanks the CSIR, India, for financial support in the form of a Senior Research Fellowship.

Supplementary data for this paper are available from the IUCr electronic archives (Reference: AB1463). Services for accessing these data are described at the back of the journal.

References

- Enraf–Nonius (1989). *CAD-4 Software*. Version 5.0. Enraf–Nonius, Delft, The Netherlands.
 Ergin, O., Sillanpää, R. & Ezer, N. (1993). *Acta Cryst. C49*, 42–44.
 Ergin, O., Sillanpää, R. & Yesilada, A. (1996). *Acta Cryst. C52*, 1770–1772.
 Ghosh, R., Lynch, V. M., Simonsen, S. H., Prasad, R. S. & Roberts, R. M. (1993). *Acta Cryst. C49*, 1013–1015.
 Jarboe, C. H. (1967). In *Pyrazoles, Pyrazolines, Pyrazolidines, Indazoles and Condensed Rings*, edited by R. H. Wiley. Gresham: John Wiley.
 Lorand, T., Szabo, D., Foldesi, A., Parkanyi, L., Kalman, A. & Neszmelyi, A. (1985). *J. Chem. Soc. Perkin Trans. 1*, pp. 481–486.
 Nardelli, M. (1983). *Comput. Chem.* **7**, 95–98.
 Sheldrick, G. M. (1990). *Acta Cryst. A46*, 467–473.
 Sheldrick, G. M. (1993). *SHELXL93. Program for the Refinement of Crystal Structures*. University of Göttingen, Germany.
 Vickovic, I. (1994). *J. Appl. Cryst.* **27**, 437.

Acta Cryst. (1998). **C54**, 630–633

Three Diphenyl Sulfones

JEYARAMAN JEYAKANTHAN,^a D. VELMURUGAN,^a K. PANNEERSELVAM,^b MANUEL SORIANO-GARCIA,^b S. PERUMAL^c AND R. CHANDRASEKARAN^c

^aDepartment of Crystallography and Biophysics, University of Madras, Guindy Campus, Madras 600 025, India,

^bInstituto de Química, UNAM, Circuito Exterior Ciudad Universitaria, Mexico DF 04510, Mexico, and ^cDepartment of Organic Chemistry, Madurai Kamaraj University, Palkalai Nagar, Madurai 21, India. E-mail: crystal@giasmd01.vsnl.net.in

(Received 3 April 1997; accepted 14 November 1997)

Abstract

In 2,6-dimethylphenyl 4-nitrophenyl sulfone, C₁₄H₁₃-NO₄S, (I), 2,6-dimethylphenyl 4-methylphenyl sulfone, C₁₅H₁₆O₂S, (II), and 2-methylphenyl phenyl sulfone, C₁₃H₁₂O₂S, (III), the S atoms have distorted tetrahedral bonding geometry. In each compound, the phenyl rings are nearly perpendicular to each other [dihedral angles: 80.0 (1) in (I), 89.6 (1) in (II) and 78.9 (1)° in (III)].

Comment

A number of diaryl sulfides, sulfones and sulfoxides display insecticidal, antibacterial, germicidal, microbial

Data collection

Enraf–Nonius CAD-4 diffractometer
 $\omega/2\theta$ scans
 Absorption correction:
 refined from ΔF
 (DIFABS; Walker & Stuart, 1983)
 $T_{\min} = 0.325$, $T_{\max} = 0.513$
 2349 measured reflections
 1788 independent reflections

1660 reflections with
 $I > 2\sigma(I)$
 $R_{\text{int}} = 0.064$
 $\theta_{\text{max}} = 56.66^\circ$
 $h = -12 \rightarrow 12$
 $k = 0 \rightarrow 11$
 $l = 0 \rightarrow 13$
 3 standard reflections
 every 200 reflections
 intensity decay: <3%

$\omega/2\theta$ scans
 Absorption correction:
 refined from ΔF
 (DIFABS; Walker & Stuart, 1983)
 $T_{\min} = 0.518$, $T_{\max} = 0.666$
 2257 measured reflections
 1822 independent reflections

$R_{\text{int}} = 0.037$
 $\theta_{\text{max}} = 56.63^\circ$
 $h = -22 \rightarrow 22$
 $k = 0 \rightarrow 11$
 $l = 0 \rightarrow 16$
 3 standard reflections
 every 200 reflections
 intensity decay: <4%

Refinement

Refinement on F^2
 $R[F^2 > 2\sigma(F^2)] = 0.037$
 $wR(F^2) = 0.113$
 $S = 0.613$
 1788 reflections
 234 parameters
 All H atoms refined
 $w = 1/[\sigma^2(F_o^2) + (0.121P)^2 + 1.59P]$
 where $P = (F_o^2 + 2F_c^2)/3$
 $(\Delta/\sigma)_{\text{max}} = 0.010$

$\Delta\rho_{\text{max}} = 0.23 \text{ e } \text{\AA}^{-3}$
 $\Delta\rho_{\text{min}} = -0.38 \text{ e } \text{\AA}^{-3}$
 Extinction correction:
 SHELXL93 (Sheldrick, 1993)
 Extinction coefficient:
 0.0080 (13)
 Scattering factors from

International Tables for Crystallography (Vol. C)

$w = 1/[\sigma^2(F_o^2) + (0.0904P)^2 + 3.072P]$
 where $P = (F_o^2 + 2F_c^2)/3$
 $(\Delta/\sigma)_{\text{max}} = -0.001$
 $\Delta\rho_{\text{max}} = 0.21 \text{ e } \text{\AA}^{-3}$
 $\Delta\rho_{\text{min}} = -0.34 \text{ e } \text{\AA}^{-3}$
 Extinction correction: none
 Scattering factors from
International Tables for Crystallography (Vol. C)

Table 1. Selected geometric parameters (\AA , $^\circ$) for (I)

S—O2	1.437 (2)	N—O3	1.228 (3)
S—O1	1.441 (2)	N—C4'	1.480 (4)
S—C1	1.791 (2)	C2—C7	1.517 (4)
S—C1'	1.788 (3)	C6—C8	1.501 (5)
N—O4	1.231 (3)		
O2—S—O1	117.81 (13)	C6—C1—S	117.2 (2)
O2—S—C1	109.33 (12)	C3—C2—C7	116.6 (3)
O1—S—C1	110.06 (12)	C1—C2—C7	126.2 (2)
O2—S—C1'	108.36 (12)	C5—C6—C8	117.1 (3)
O1—S—C1'	105.53 (12)	C1—C6—C8	125.6 (3)
C1—S—C1'	104.92 (11)	C6'—C1'—S	119.7 (2)
O4—N—O3	124.2 (3)	C2'—C1'—S	118.7 (2)
O4—N—C4'	117.6 (3)	C3'—C4'—N	118.0 (3)
O3—N—C4'	118.2 (3)	C5'—C4'—N	118.7 (2)
C2—C1—S	121.0 (2)		

Compound (II)*Crystal data*
 $M_r = 260.34$

Monoclinic

 $C2/c$
 $a = 20.339$ (7) \AA
 $b = 11.024$ (4) \AA
 $c = 15.220$ (7) \AA
 $\beta = 126.80$ (2) $^\circ$
 $V = 2732.6$ (19) \AA^3
 $Z = 8$
 $D_x = 1.266 \text{ Mg m}^{-3}$
 D_m not measured
Cu K α radiation
 $\lambda = 1.54178 \text{ \AA}$

Cell parameters from 21 reflections

 $\theta = 15\text{--}30^\circ$
 $\mu = 2.0 \text{ mm}^{-1}$
 $T = 293$ (2) K

Tabular

 $0.4 \times 0.3 \times 0.2 \text{ mm}$

Colourless

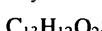
Data collection

Enraf–Nonius CAD-4 diffractometer
 $\omega/2\theta$ scans
 Absorption correction:
 refined from ΔF
 (DIFABS; Walker & Stuart, 1983)
 $T_{\min} = 0.391$, $T_{\max} = 0.625$
 1936 measured reflections
 1832 independent reflections

$R_{\text{int}} = 0.039$
 $\theta_{\text{max}} = 62.50^\circ$
 $h = -14 \rightarrow 14$
 $k = 0 \rightarrow 9$
 $l = 0 \rightarrow 13$
 3 standard reflections
 every 100 reflections
 intensity decay: <3%

Table 2. Selected geometric parameters (\AA , $^\circ$) for (II)

S—O2	1.434 (2)	C2—C7	1.495 (5)
S—O1	1.439 (2)	C6—C8	1.512 (5)
S—C1'	1.771 (3)	C4'—C7'	1.511 (5)
S—C1	1.781 (3)		
O2—S—O1	117.01 (15)	C3—C2—C7	117.0 (3)
O2—S—C1'	107.22 (14)	C1—C2—C7	125.7 (3)
O1—S—C1'	108.32 (14)	C1—C6—C8	126.1 (3)
O2—S—C1	109.99 (15)	C5—C6—C8	117.0 (3)
O1—S—C1	109.80 (14)	C2'—C1'—S	120.8 (2)
C1'—S—C1	103.61 (13)	C6'—C1'—S	118.6 (2)
C6—C1—S	121.2 (2)	C5'—C4'—C7'	120.8 (4)
C2—C1—S	117.0 (2)	C3'—C4'—C7'	121.1 (4)

Compound (III)*Crystal data*
 $M_r = 232.29$

Monoclinic

 $P2_1/c$
 $a = 12.360$ (5) \AA
 $b = 8.246$ (4) \AA
 $c = 11.615$ (7) \AA
 $\beta = 103.74$ (3) $^\circ$
 $V = 1149.9$ (10) \AA^3
 $Z = 4$
 $D_x = 1.342 \text{ Mg m}^{-3}$
 D_m not measured
Cu K α radiation
 $\lambda = 1.54178 \text{ \AA}$

Cell parameters from 21 reflections

 $\theta = 13\text{--}28^\circ$
 $\mu = 2.3 \text{ mm}^{-1}$
 $T = 293$ (2) K

Tabular

 $0.4 \times 0.3 \times 0.2 \text{ mm}$

Colourless

Data collection

Enraf–Nonius CAD-4 diffractometer
 $\omega/2\theta$ scans
 Absorption correction:
 refined from ΔF
 (DIFABS; Walker & Stuart, 1983)
 $T_{\min} = 0.391$, $T_{\max} = 0.625$
 1740 reflections with
 $I > 2\sigma(I)$
 $R_{\text{int}} = 0.039$
 $\theta_{\text{max}} = 62.50^\circ$
 $h = -14 \rightarrow 14$
 $k = 0 \rightarrow 9$
 $l = 0 \rightarrow 13$
 3 standard reflections
 every 100 reflections
 intensity decay: <3%

Data collection

Enraf–Nonius CAD-4 diffractometer

1616 reflections with
 $I > 2\sigma(I)$

Refinement

Refinement on F^2	$(\Delta/\sigma)_{\text{max}} = -0.033$
$R[F^2 > 2\sigma(F^2)] = 0.057$	$\Delta\rho_{\text{max}} = 0.48 \text{ e } \text{\AA}^{-3}$
$wR(F^2) = 0.162$	$\Delta\rho_{\text{min}} = -0.35 \text{ e } \text{\AA}^{-3}$
$S = 1.186$	Extinction correction:
1832 reflections	<i>SHELXL93</i> (Sheldrick, 1993)
182 parameters	Extinction coefficient: 0.006 (2)
H atoms fixed (H atoms on C7 riding)	Scattering factors from <i>International Tables for Crystallography</i> (Vol. C)
$w = 1/[\sigma^2(F_o^2) + (0.0942P)^2 + 0.5159P]$ where $P = (F_o^2 + 2F_c^2)/3$	

Table 3. Selected geometric parameters (\AA , $^\circ$) for (III)

S—O1	1.436 (2)	S—C1	1.777 (3)
S—O2	1.444 (2)	C2—C7	1.502 (4)
S—C1'	1.768 (3)		
O1—S—O2	118.41 (14)	C6—C1—S	115.9 (2)
O1—S—C1'	108.29 (13)	C2—C1—S	123.1 (2)
O2—S—C1'	107.43 (13)	C3—C2—C7	118.7 (3)
O1—S—C1	110.34 (13)	C1—C2—C7	125.4 (3)
O2—S—C1	106.90 (13)	C6'—C1'—S	119.2 (2)
C1'—S—C1	104.58 (11)	C2'—C1'—S	119.9 (2)

Table 4. Selected dihedral angles ($^\circ$) for (I), (II) and (III)

	Ar/Ar	C—S—C/C1—C6	C—S—C/C1'—C6'
(I)	80.0 (1)	108.7 (1)	63.3 (1)
(II)	89.6 (1)	110.4 (1)	120.9 (1)
(III)	78.9 (1)	95.8 (1)	82.6 (1)

For all compounds, data collection: *SDP* (Frenz, 1978); cell refinement: *SDP*; data reduction: *SDP*; program(s) used to solve structures: *SHELXS86* (Sheldrick, 1985); program(s) used to refine structures: *SHELXL93* (Sheldrick, 1993); molecular graphics: *ORTEP92* (Vickovic, 1994); software used to prepare material for publication: *PARST* (Nardelli, 1983).

Supplementary data for this paper are available from the IUCr electronic archives (Reference: FR1058). Services for accessing these data are described at the back of the journal.

References

- Chandrasekaran, R. (1991). *Studies on Organic Sulfur Compounds*. PhD thesis, Madurai Kamaraj University, India.
- De Benedetti, P. G., Folli, U., Iarossi, D. & Frassineti, C. (1985). *J. Chem. Soc. Perkin Trans. 2*, pp. 1527–1532.
- Frenz, B. A. (1978). *The Enraf–Nonius CAD-4 SDP – a Real-Time System for Concurrent X-ray Data Collection and Crystal Structure Solution. Computing in Crystallography*, edited by H. Schenk, R. Olthof-Hazekamp, H. van Koningsveld & G. C. Bassi, pp. 64–71. Delft University Press.
- Gzella, A., Wrzeciono, U., Dudzinska-Usarewicz, J. & Borowiak, T. (1989). *Acta Cryst. C45*, 642–644.
- Nardelli, M. (1983). *Comput. Chem.* **7**, 95–98.
- Sheldrick, G. M. (1985). *SHELXS86. Program for the Solution of Crystal Structures*. University of Göttingen, Germany.
- Sheldrick, G. M. (1993). *SHELXL93. Program for the Refinement of Crystal Structures*. University of Göttingen, Germany.
- Sime, J. G. & Woodhouse, D. J. (1974). *J. Cryst. Mol. Struct.* **4**, 269–285.
- Tiwari, R. K., Haridas, M. & Singh, T. P. (1984). *Acta Cryst. C40*, 655–657.
- Vickovic, I. (1994). *J. Appl. Cryst.* **27**, 437.
- Walker, N. & Stuart, D. (1983). *Acta Cryst. A39*, 158–166.

Acta Cryst. (1998). **C54**, 633–635**9-(4-Methoxyphenyl)-10-phenyl-3,4,6,7,9,10-hexahydro-1,8(2H,5H)-acridinedione**V. K. GANESH,^a S. BANUMATHI,^a D. VELMURUGAN,^a N. RAMASUBBU^b AND V. T. RAMAKRISHNAN^c^aDepartment of Crystallography and Biophysics, University of Madras, Guindy Campus, Madras 600 025, India,^bDepartment of Oral Biology and Dental Research, School of Dental Medicine, State University of New York, Buffalo, NY 14214, USA, and ^cDepartment of Organic Chemistry, University of Madras, Guindy Campus, Madras 600 025, India. E-mail: crystal@giiasmd01.vsnl.net.in

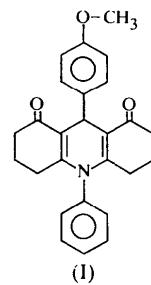
(Received 6 August 1996; accepted 17 November 1997)

Abstract

In the title compound, $C_{26}H_{25}NO_3$, the central ring adopts a distorted boat conformation and the outer rings adopt half-chair conformations. The molecule is stabilized by C—H···O-type hydrogen bonds.

Comment

The interactions of acridine with DNA are generally known to be partly responsible for their biological activities (Neidle, 1979). Acridines of the same type as the title compound, (I), have been observed to fluoresce well as laser dyes in alcohol solvents (Selladurai *et al.*, 1990).



The bond lengths in the pyridine ring range from 1.348 (3) to 1.511 (3) \AA and show the respective greater or lesser degree of single- or double-bond character as predicted from comparisons with related acridine structures (Selladurai *et al.*, 1989, 1990; Sivaraman *et al.*, 1994, 1996). The C—N distances in the acridinyl ring have an average value of 1.395 (5) \AA and the mean C—N—C angle is 119.8 (3) $^\circ$. These values agree well with those for related acridinyl derivatives (Chu & Van der Helm, 1977).

The ketone bond lengths C6—O6' and C10—O10' of 1.227 (3) and 1.229 (3) \AA , respectively, are in agreement with values observed for related structures (Dideberg *et*